

# *Digital Photography VIII*

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**23–24 January 2012  
Burlingame, California, United States**

*Sponsored and Published by*  
IS&T—The Society for Imaging Science and Technology  
SPIE

**Volume 8299**

The papers included in this volume were part of the technical conference cited on the cover and title page. Papers were selected and subject to review by the editors and conference program committee. Some conference presentations may not be available for publication. The papers published in these proceedings reflect the work and thoughts of the authors and are published herein as submitted. The publishers are not responsible for the validity of the information or for any outcomes resulting from reliance thereon.

Please use the following format to cite material from this book:

Author(s), "Title of Paper," in *Digital Photography VIII*, edited by Sebastiano Battiato, Brian G. Rodricks, Nitin Sampat, Francisco H. Imai, Feng Xiao, Proceedings of SPIE-IS&T Electronic Imaging, SPIE Vol. 8299, Article CID Number (2012).

ISSN 0277-786X

ISBN 9780819489463

Copublished by

**SPIE**

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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Printed in the United States of America.

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